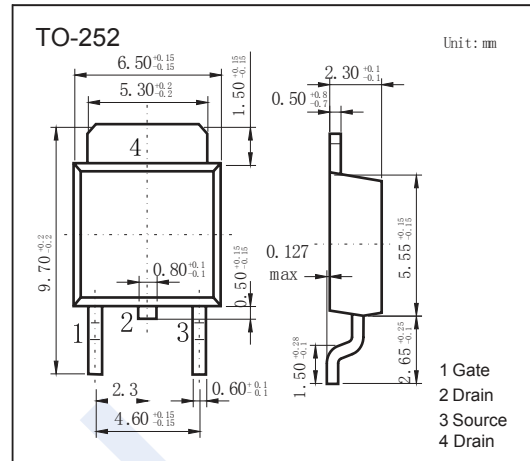
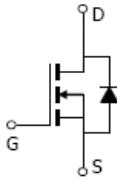


## N-Channel MOSFET

### NDT2N60

#### ■ Features

- $V_{DS} (V) = 600V$
- $I_D = 2 A (V_{GS} = 10V)$
- $R_{DS(ON)} < 4.5 \Omega (V_{GS} = 10V)$
- Low Gate Charge
- Low Reverse transfer capacitances



#### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	600	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	
Gate source ESD (HBM-C= 100pF, R=1.5k $\Omega$ )	$V_{ESD}$	3000	
Continuous Drain Current	$I_D$	2	A
		$T_c=100^\circ\text{C}$	
Pulsed Drain Current	$I_{DM}$	8	
Avalanche Current	$I_{AR}$	1.1	
Avalanche Energy ,Repetitive	(Note.1) $E_{AR}$	6.4	mJ
Single Pulse Avalanche Energy	$E_{AS}$	80	
Peak Diode Recovery dv/dt	(Note.2) $dv/dt$	5	V/ns
Power Dissipation	$P_D$	35	W
Derating Factor above $25^\circ\text{C}$		0.28	$W/^\circ\text{C}$
Thermal Resistance.Junction- to-Ambient	$R_{thJA}$	62	$^\circ\text{C}/\text{W}$
Thermal Resistance.Junction- to-Lead	$R_{thJL}$	3.57	
Junction Temperature	$T_J$	150	$^\circ\text{C}$
Maximum Temperature for Soldering	$T_L$	300	
Storage Temperature Range	$T_{stg}$	-55 to 150	

Note.1:  $L=10\text{mH}$ ,  $I_D=4\text{A}$ , Start  $T_J=25^\circ\text{C}$

Note.2:  $I_{SD} = 2\text{A}$ ,  $di/dt \leq 100\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DS}$ , Start  $T_J=25^\circ\text{C}$

## N-Channel MOSFET

### NDT2N60

#### ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>bss</sub>	I <sub>D</sub> =250 μA, V <sub>GS</sub> =0V	600			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V			1	μA
		V <sub>DS</sub> =480V, V <sub>GS</sub> =0V, Ta=125°C			100	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±30V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2		4	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =1A			4.5	Ω
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =1A		1.8		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1MHz		280		pF
Output Capacitance	C <sub>oss</sub>			31		
Reverse Transfer Capacitance	C <sub>rss</sub>			5.4		
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =300V, I <sub>D</sub> =2A		8.5		nC
Gate Source Charge	Q <sub>gs</sub>			1.5		
Gate Drain Charge	Q <sub>gd</sub>			4		
Turn-On DelayTime	t <sub>d(on)</sub>	V <sub>DS</sub> =300V, I <sub>D</sub> =2A, R <sub>GEN</sub> =9.1Ω		7		ns
Turn-On Rise Time	t <sub>r</sub>			5		
Turn-Off DelayTime	t <sub>d(off)</sub>			26		
Turn-Off Fall Time	t <sub>f</sub>			10.5		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 2A, di/dt= 100A/us, T <sub>J</sub> =25°C		407		nC
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			1152		
Maximum Body-Diode Continuous Current	I <sub>S</sub>				2	A
Maximum Pulsed Current (Body Diode)	I <sub>SM</sub>				8	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =2A, V <sub>GS</sub> =0V			1.5	V

Note. Pulse width  $t_p \leq 380\mu s$ ,  $\delta \leq 2\%$

## N-Channel MOSFET NDT2N60

■ Typical Characteristics

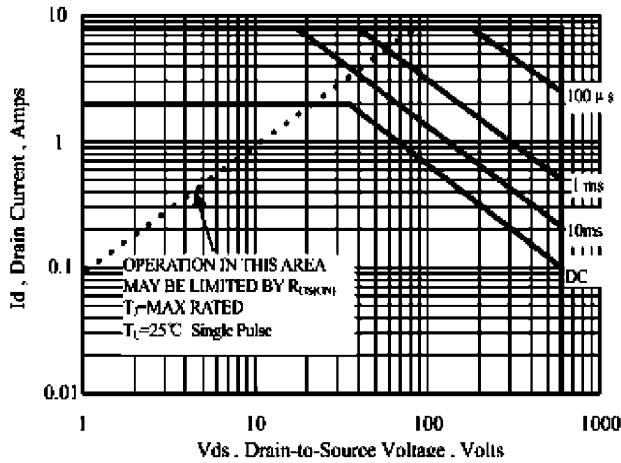


Figure 1 Maximum Forward Bias Safe Operating Area

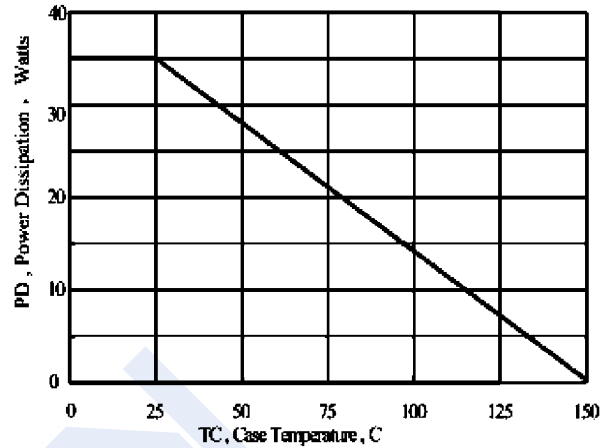


Figure 2 Maximum Power Dissipation vs Case Temperature

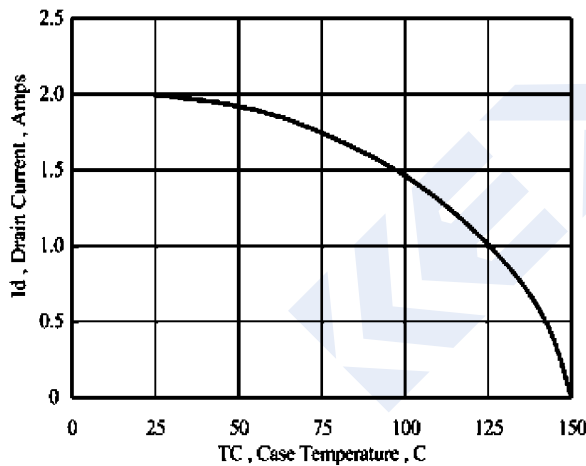


Figure 3 Maximum Continuous Drain Current vs Case Temperature

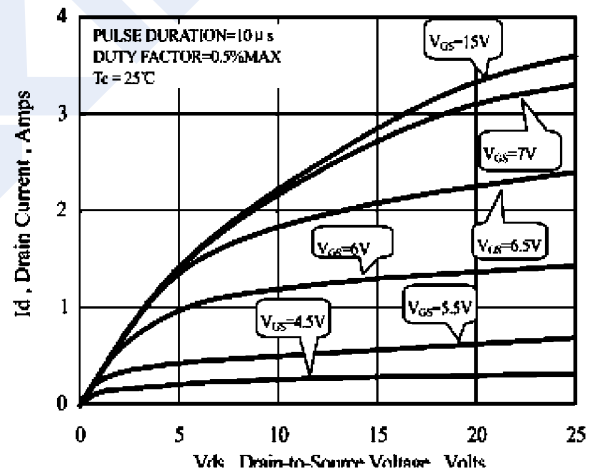


Figure 4 Typical Output Characteristics

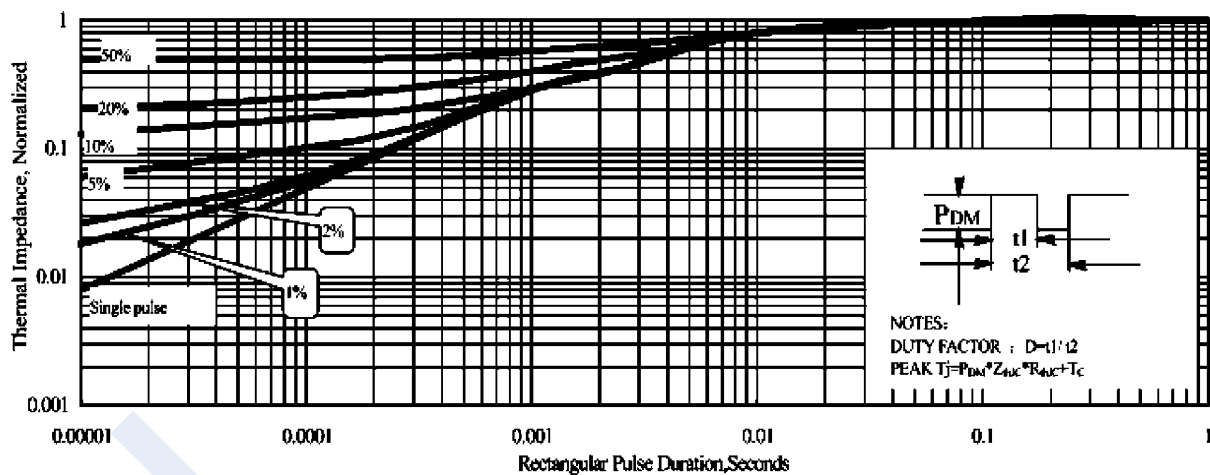
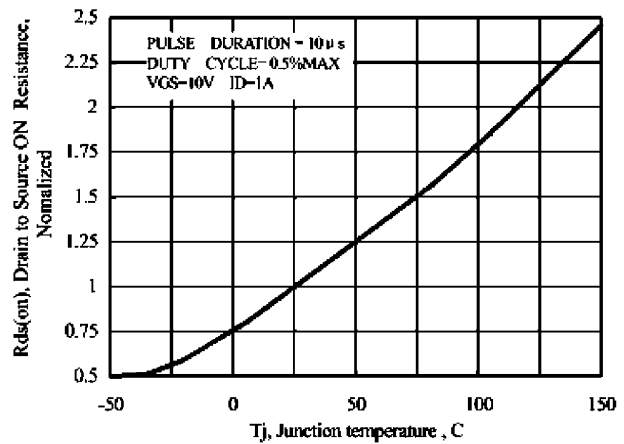
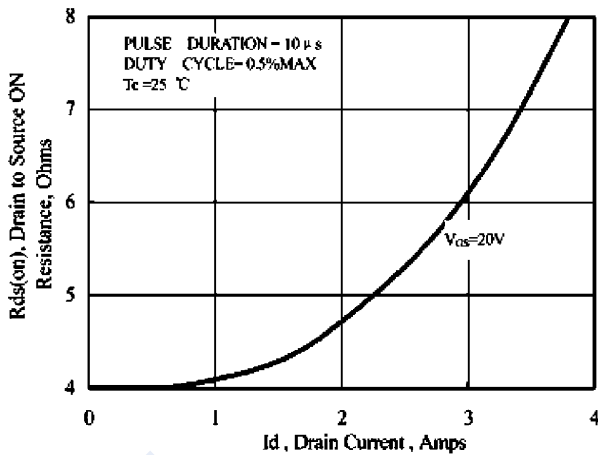
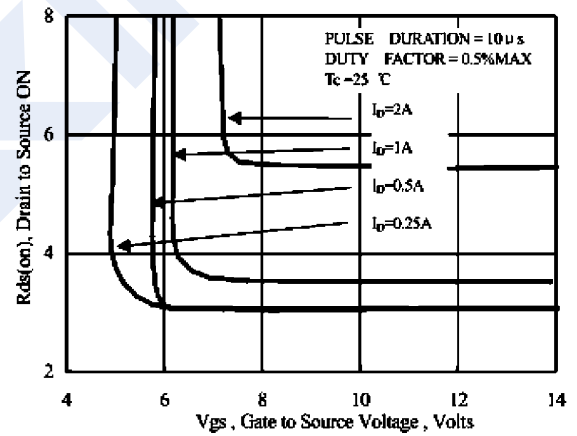
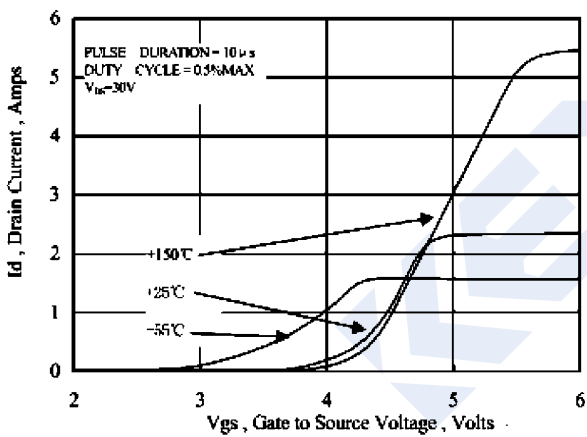
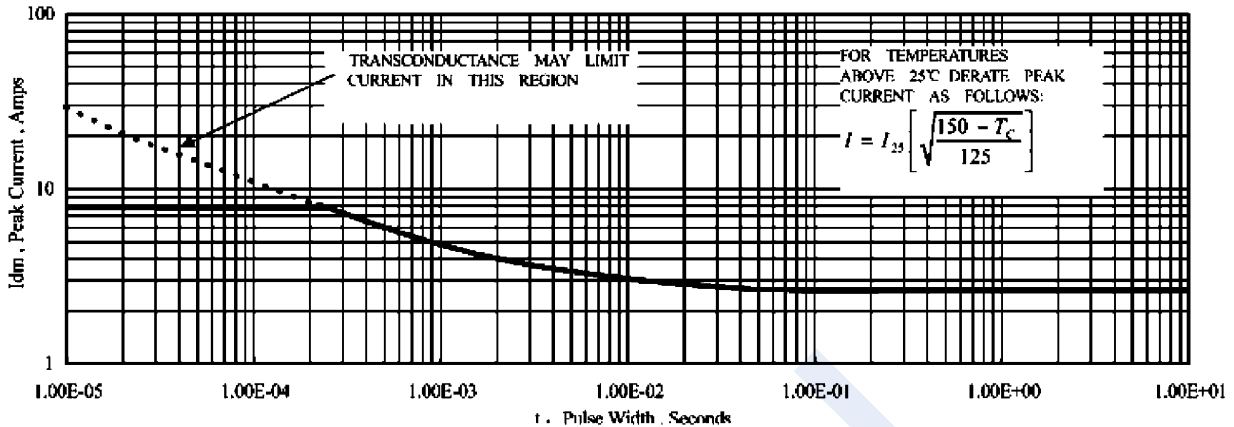


Figure 5 Maximum Effective Thermal Impedance, Junction to Case

## N-Channel MOSFET NDT2N60

■ Typical Characteristics



## N-Channel MOSFET NDT2N60

■ Typical Characteristics

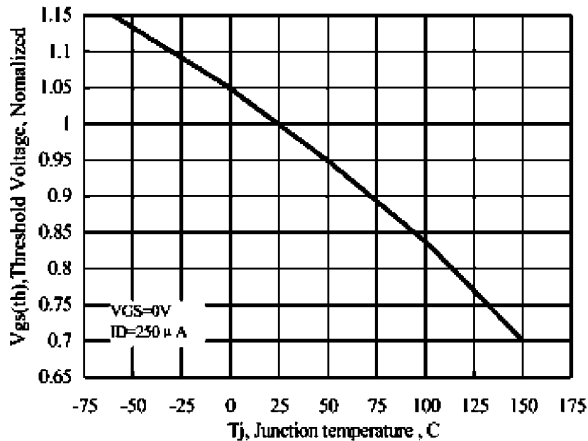


Figure 11 Typical Threshold Voltage vs Junction Temperature

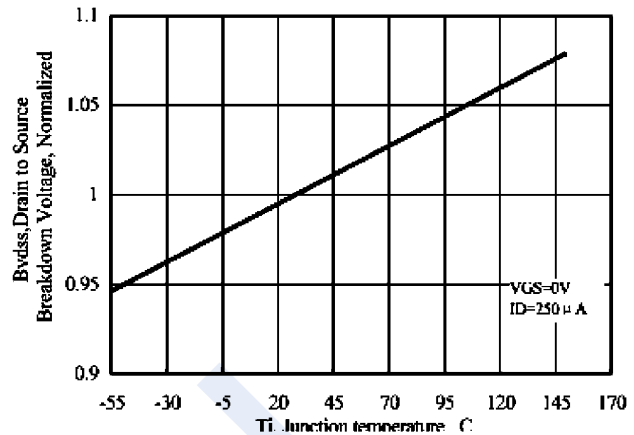


Figure 12 Typical Breakdown Voltage vs Junction Temperature

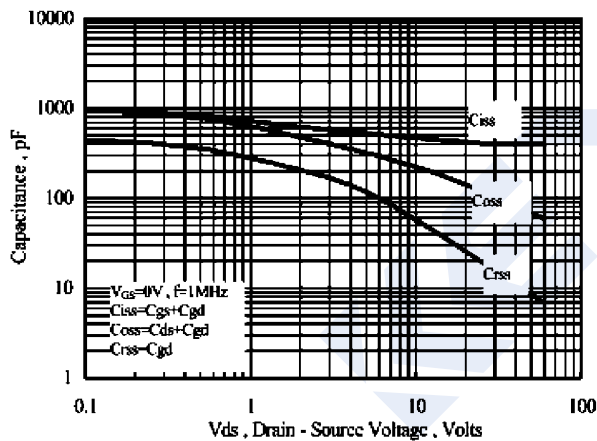


Figure 13 Typical Capacitance vs Drain to Source Voltage

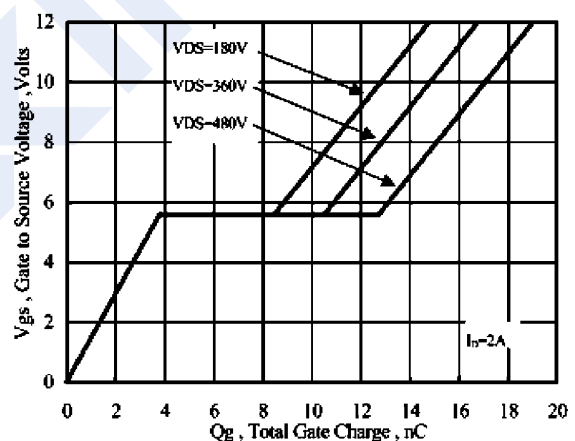


Figure 14 Typical Gate Charge vs Gate to Source Voltage

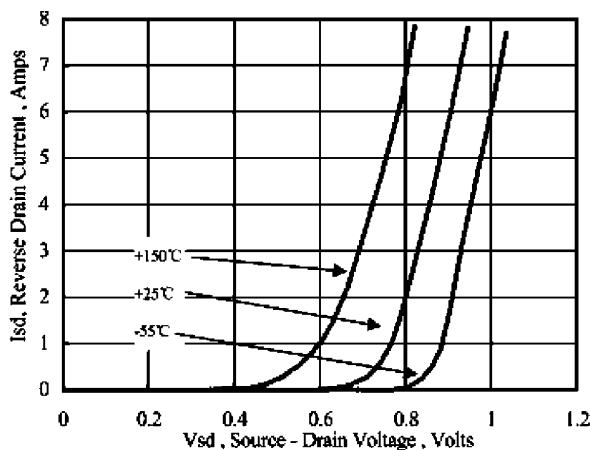


Figure 15 Typical Body Diode Transfer Characteristics

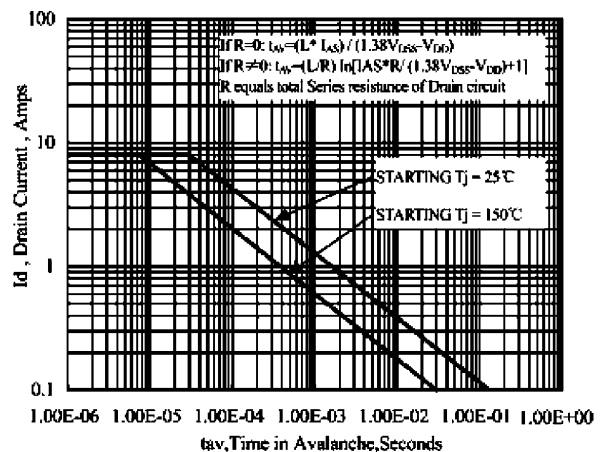


Figure 16 Unclamped Inductive Switching Capability